



## Dual N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V)	$r_{DS(on)}$ ( $\Omega$ )	$I_D$ (A)
30	0.0095 @ $V_{GS} = 10$ V	15.3
	0.016 @ $V_{GS} = 4.5$ V	11.8

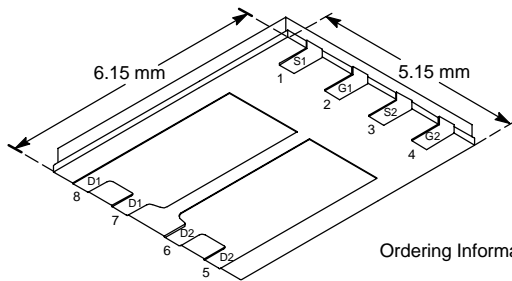
### FEATURES

- TrenchFET® Power MOSFET
- New Low Thermal Resistance PowerPAK® Package with Low 1.07-mm Profile
- 100%  $R_g$  Tested

### APPLICATIONS

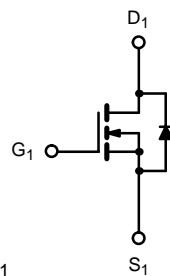
- DC/DC Conversion
- Logic Level

PowerPAK SO-8

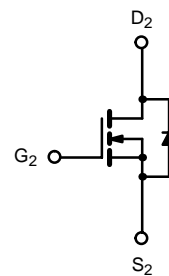


Bottom View

Ordering Information: Si7944DP-T1



N-Channel MOSFET



N-Channel MOSFET

### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter		Symbol	10 secs	Steady State	Unit
Drain-Source Voltage		$V_{DS}$	30		V
Gate-Source Voltage		$V_{GS}$	$\pm 20$		
Continuous Drain Current ( $T_J = 150^\circ\text{C}$ ) <sup>a</sup>	$T_A = 25^\circ\text{C}$	$I_D$	15.3	9.8	A
	$T_A = 85^\circ\text{C}$		11.0	7.1	
Pulsed Drain Current		$I_{DM}$	30		
Continuous Source Current (Diode Conduction) <sup>a</sup>		$I_S$	3	1.2	W
Maximum Power Dissipation <sup>a</sup>	$T_A = 25^\circ\text{C}$	$P_D$	3.6	1.5	
	$T_A = 85^\circ\text{C}$		1.9	0.8	
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	-55 to 150		$^\circ\text{C}$

### THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>a</sup>	$t \leq 10$ sec	$R_{thJA}$	26	35	$^\circ\text{C/W}$
	Steady State		60	85	
Maximum Junction-to-Case (Drain)		$R_{thJC}$	2.5	3.1	

Notes

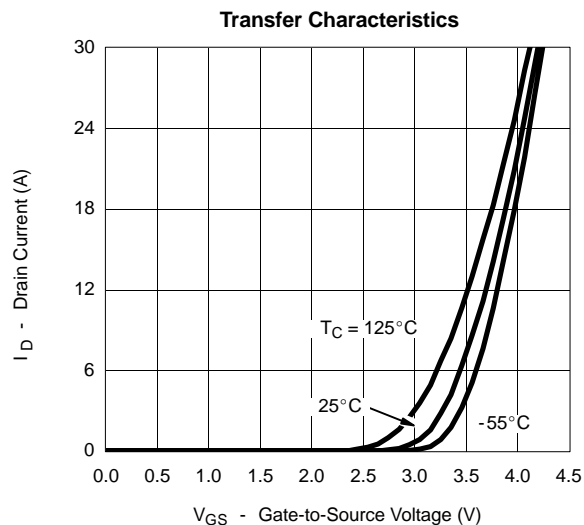
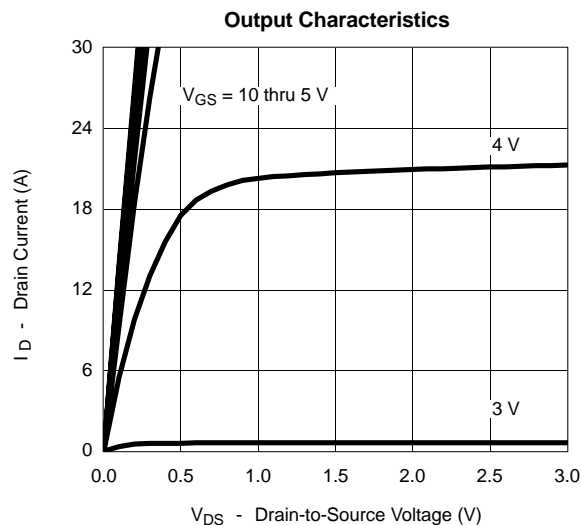
a. Surface Mounted on 1" x 1" FR4 Board.

**MOSFET SPECIFICATIONS ( $T_J = 25^\circ\text{C}$  UNLESS OTHERWISE NOTED)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1		3	V
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$			5	
On-State Drain Current <sup>NO TAG</sup>	$I_{D(on)}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			A
Drain-Source On-State Resistance <sup>NO TAG</sup>	$r_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 15.3 \text{ A}$		0.0075	0.0095	$\Omega$
		$V_{GS} = 4.5 \text{ V}, I_D = 11.8 \text{ A}$		0.013	0.016	
Forward Transconductance <sup>NO TAG</sup>	$g_{fs}$	$V_{DS} = 10 \text{ V}, I_D = 15.3 \text{ A}$		32		S
Diode Forward Voltage <sup>NO TAG</sup>	$V_{SD}$	$I_S = 3 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
<b>Dynamic<sup>NO TAG</sup></b>						
Total Gate Charge	$Q_g$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 15.3 \text{ A}$		13.5	21	nC
Gate-Source Charge	$Q_{gs}$			7.1		
Gate-Drain Charge	$Q_{gd}$			4.7		
Gate Resistance	$R_g$		0.5	1.0	1.7	$\Omega$
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$ $I_D \cong 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 6 \Omega$		10	15	ns
Rise Time	$t_r$			10	15	
Turn-Off Delay Time	$t_{d(off)}$			40	60	
Fall Time	$t_f$			12	20	
Source-Drain Reverse Recovery Time	$t_{rr}$	$I_F = 2.3 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$		45	70	

## Notes

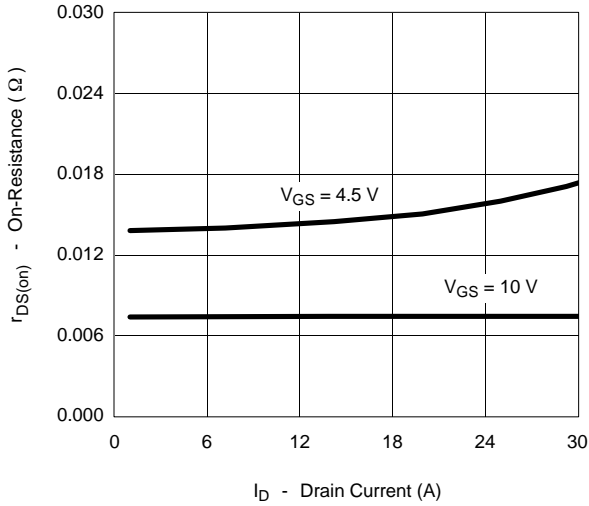
- Pulse test; pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .
- Guaranteed by design, not subject to production testing.

**TYPICAL CHARACTERISTICS ( $25^\circ\text{C}$  UNLESS NOTED)**

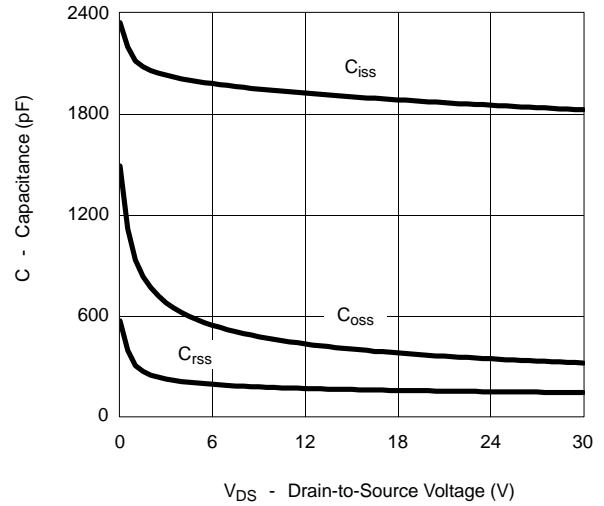


**TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)**

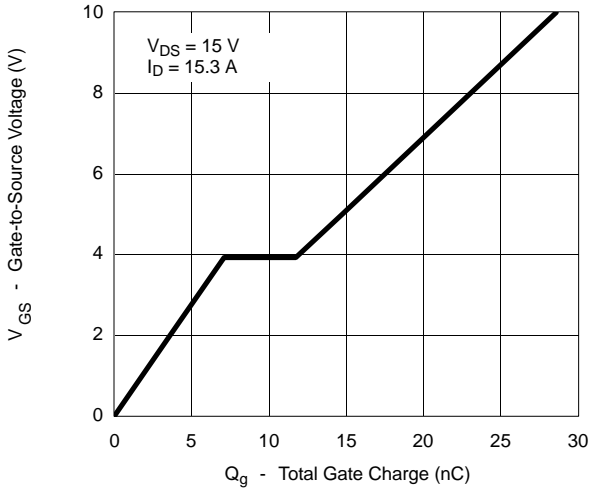
On-Resistance vs. Drain Current



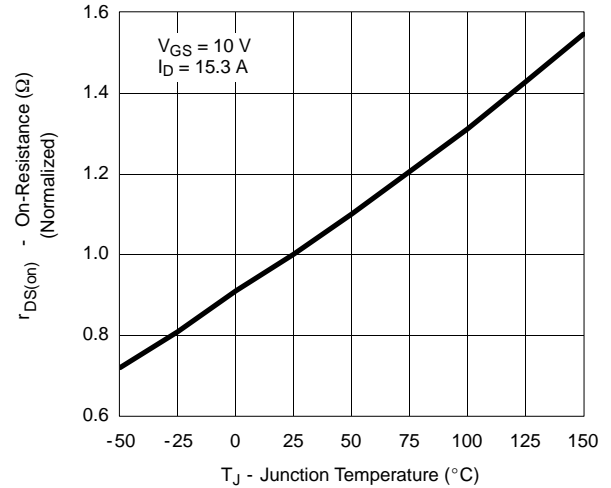
Capacitance



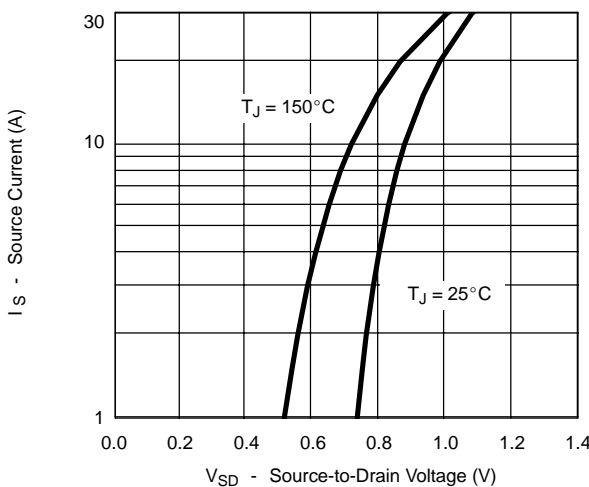
Gate Charge



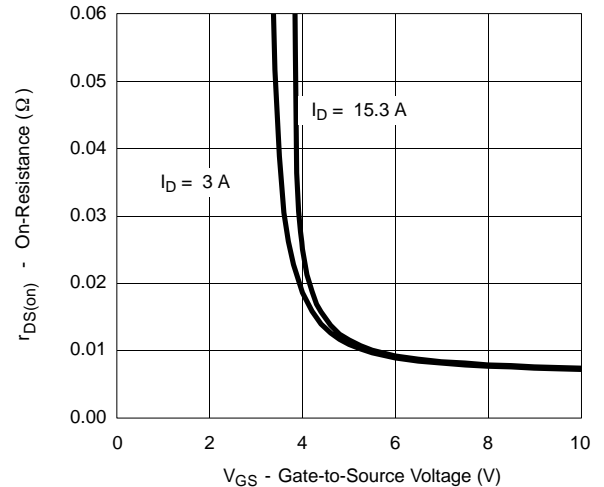
On-Resistance vs. Junction Temperature



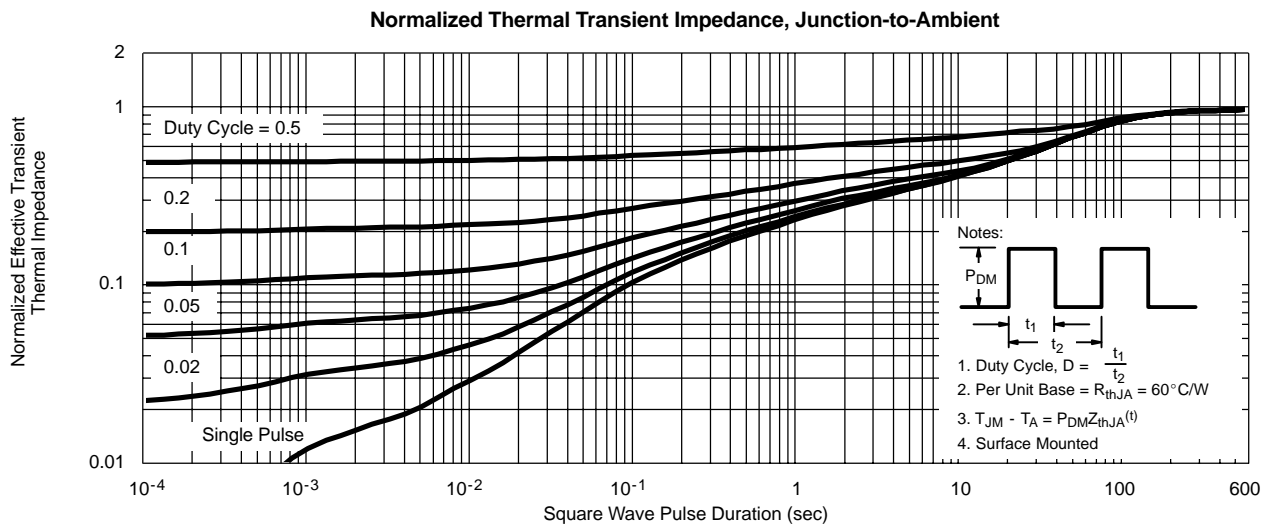
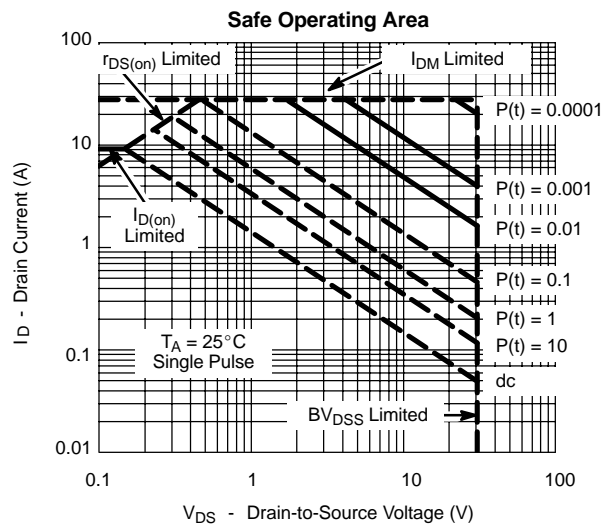
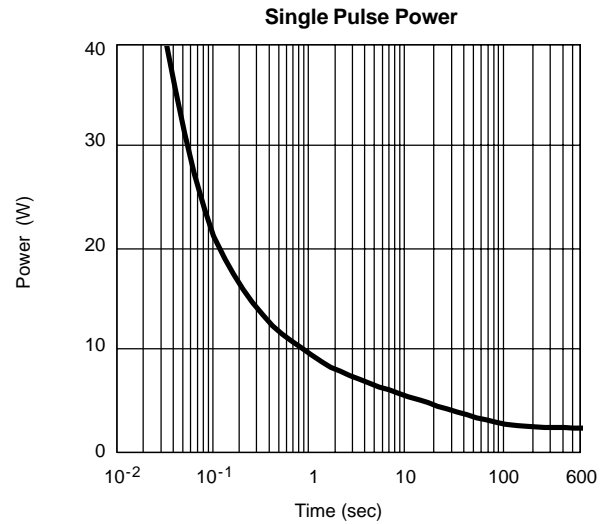
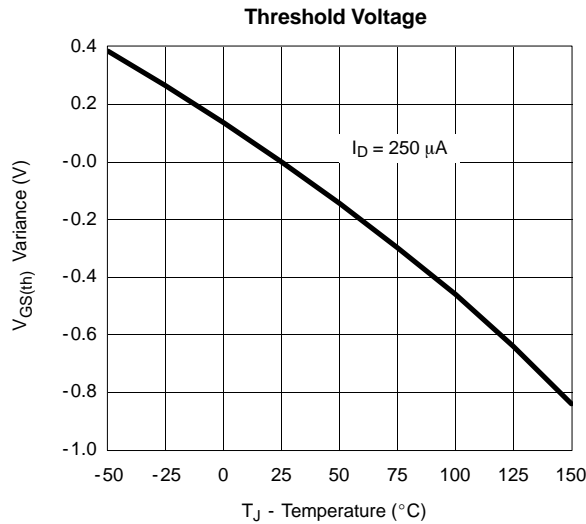
Source-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



**TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)**





**TYPICAL CHARACTERISTICS (25 °C UNLESS NOTED)**

